Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/717,216	IMAI, KATSUHIKO	
Examiner	Art Unit	
Phi D. A	3637	

	SEARCHED				
Class	Subclass	Date	Examiner		
52	167.1	6/11/2006	PA		
	167.7				
	167.8				
	167.9				
	251				
	348				
	344				
	350				

INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		
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SEARCH NO (INCLUDING SEARCI	OTES H STRATEGY	7)
	DATE	EXMR
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